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## Segregation to creep-induced planar faults in Ni-base SX superalloys

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Ni-base single-crystal (SX) superalloys find application in turbine blades for gas engines due to the high-temperature and high-stress strength originating from the coherent  $\gamma/\gamma'$  microstructure. It is well-known at sufficiently high stresses, two  $1/2\langle 101 \rangle$  dislocation families with different Burgers vector can react and dissociate into two partial dislocations in  $\gamma$  channels. This allows the leading  $1/3[-1-12]$  Shockley partial dislocation continuously gliding on  $\{111\}$  planes to cut into  $\gamma'$  precipitates where they create planar faults [1]. We study the segregation behaviours of alloying elements across the planar faults by performing the  $[11-2]$  (111) creep shear experiments, to intentionally activate the slip system  $[11-2]$  (111) with the highest Schmid factor of 1 where the resolved shear stress is exactly equal to loading stress. The creep-deformed specimens are interrupted after 1% and 2% shear strain under 250 MPa at 750 °C. The resulting microstructure is investigated using conventional transmission electron microscopy (TEM), analytical scanning TEM (STEM) with energy-dispersive X-ray spectroscopy (EDXS) focussing on structural, physical, and chemical details of the local deformation.

We investigated the specimen perpendicular to the (111) plane with the  $[1-10]$  direction parallel to the electron beam. Numerous stacking faults (SF) are observed after 1% and 2% creep strains. Fringe contrasts under two-beam conditions indicate inclined stacking faults, where the 2% strain sample has more planar faults within one  $\gamma'$  precipitate indicating a higher density of planar faults in the 2% sample. High-resolution STEM micrographs illustrate the superlattice extrinsic nature of stacking faults (SESF) in the 1% and 2% strained samples. The chemical distributions across SESF are measured by EDXS and the corresponding concentration profile of 1% and 2% samples. Both samples show almost similar segregation tendency, which is that  $\gamma$  forming elements Cr, Co and Re are enriched across the SESF while  $\gamma'$  alloying elements Ni and Al are depleted, which is partly in agreement with theoretical predictions [2]. For these measurements all microscope parameters and sample thickness for EDXS analysis are kept the same to quantitatively find out how creep strain and time affect the evolution of segregation.

### Category

Solid State (Experiment)

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